

# MBN2400F17F

## Preliminary Specification

Silicon N-channel IGBT 1700V F version

### FEATURES

- \* Soft switching behavior, low switching loss & low conduction loss :  
Soft low-injection punch-through with trench gate IGBT
- \* Low driving power due to low input capacitance advanced trench MOS gate.
- \* Ultra soft fast recovery diode.
- \* High current rate package.
- \* Low  $R_{th(j-c)}$  & low stray inductance.
- \* RoHS
- \* High thermal fatigue durability

### ABSOLUTE MAXIMUM RATINGS ( $T_C=25^\circ\text{C}$ )

| Item                      | Symbol             | Unit             | MBN2400F17F        |
|---------------------------|--------------------|------------------|--------------------|
| Collector Emitter Voltage | $V_{CES}$          | V                | 1,700              |
| Gate Emitter Voltage      | $V_{GES}$          | V                | $\pm 20$           |
| Collector Current         | DC                 | $I_C$            | 2,400              |
|                           | 1ms                | $I_{CRM}$        | 4,800              |
| Forward Current           | DC                 | $I_F$            | 2,400              |
|                           | 1ms                | $I_{FRM}$        | 4,800              |
| Junction Temperature      | $T_{vj\text{ op}}$ | $^\circ\text{C}$ | -50 ~ +150         |
| Storage Temperature       | $T_{stg}$          | $^\circ\text{C}$ | -50 ~ +150         |
| Isolation Voltage         | $V_{ISO}$          | $V_{RMS}$        | 4,000(AC 1 minute) |
| Screw Torque              | Terminals (M4/M8)  | -                | 2/15 (1)           |
|                           | Mounting (M6)      | -                | 6 (2)              |

Notes: (1) Recommended Value  $1.8 \pm 0.2 / 15^{+0.3} \text{N}\cdot\text{m}$  (2) Recommended Value  $5.5 \pm 0.5 \text{N}\cdot\text{m}$

### ELECTRICAL CHARACTERISTICS

| Item                                 | Symbol        | Unit          | Min. | Typ.  | Max.  | Test Conditions   |
|--------------------------------------|---------------|---------------|------|-------|-------|---|
| Collector Emitter Cut-Off Current    | $I_{CES}$     | mA            | -    | -     | 7     | $V_{CE}=1,700\text{V}, V_{GE}=0\text{V}, T_{vj}=25^\circ\text{C}$               |
|                                      |               |               | -    | 30    | 100   | $V_{CE}=1,700\text{V}, V_{GE}=0\text{V}, T_{vj}=150^\circ\text{C}$              |
| Gate Emitter Leakage Current         | $I_{GES}$     | nA            | -500 | -     | +500  | $V_{GE}=\pm 20\text{V}, V_{CE}=0\text{V}, T_{vj}=25^\circ\text{C}$              |
|                                      |               |               | -    | 2.0   | -     | $I_C=2,400\text{A}, V_{GE}=15\text{V}, T_{vj}=25^\circ\text{C}$                 |
| Collector Emitter Saturation Voltage | $V_{CE(sat)}$ | V             | -    | 2.3   | -     | $I_C=2,400\text{A}, V_{GE}=15\text{V}, T_{vj}=125^\circ\text{C}$                |
|                                      |               |               | -    | 2.4   | TBD   | $I_C=2,400\text{A}, V_{GE}=15\text{V}, T_{vj}=150^\circ\text{C}$                |
|                                      |               |               | -    | -     | -     | $V_{CE}=10\text{V}, I_C=240\text{mA}, T_{vj}=25^\circ\text{C}$                  |
| Gate Emitter Threshold Voltage       | $V_{GE(th)}$  | V             | 4.1  | 5.5   | 7.1   | $V_{CE}=10\text{V}, I_C=240\text{mA}, T_{vj}=25^\circ\text{C}$                  |
| Input Capacitance                    | $C_{ies}$     | nF            | -    | 131   | -     | $V_{CE}=10\text{V}, V_{GE}=0\text{V}, f=100\text{kHz}, T_{vj}=25^\circ\text{C}$ |
| Internal Gate Resistance             | $R_{G(int)}$  | $\Omega$      | -    | 1.5   | -     | $V_{CE}=10\text{V}, V_{GE}=0\text{V}, f=100\text{kHz}, T_{vj}=25^\circ\text{C}$ |
| Turn On Delay Time                   | $t_{d(on)}$   | $\mu\text{s}$ | -    | 0.8   | TBD   | $V_{CC}=900\text{V}, I_C=2,400\text{A}$   |
| Rise Time                            | $t_r$         |               | -    | 0.2   | TBD   | $L_S=55\text{nH}$ (3)   |
| Turn Off Delay Time                  | $t_{d(off)}$  |               | -    | 1.7   | TBD   | $R_G(\text{on/off})=3.3/3.3\Omega$ (3)  |
| Fall Time                            | $t_f$         |               | -    | 1.5   | TBD   | $V_{GE}=\pm 15\text{V}, T_{vj}=150^\circ\text{C}$                               |
| Peak Forward Voltage Drop            | $V_F$         | V             | -    | 2.0   | -     | $I_F=2,400\text{A}, V_{GE}=0\text{V}, T_{vj}=25^\circ\text{C}$                  |
|                                      |               |               | -    | 2.2   | -     | $I_F=2,400\text{A}, V_{GE}=0\text{V}, T_{vj}=125^\circ\text{C}$                 |
|                                      |               |               | -    | 2.25  | TBD   | $I_F=2,400\text{A}, V_{GE}=0\text{V}, T_{vj}=150^\circ\text{C}$                 |
| Reverse Recovery Time                | $t_{rr}$      | $\mu\text{s}$ | -    | 0.85  | TBD   | $V_{CC}=900\text{V}, I_C=2,400\text{A}$   |
| Turn On Loss                         | $E_{on}$      | J/P           | -    | 0.7   | -     | $L_S=55\text{nH}$ (3)   |
| Turn Off Loss                        | $E_{off}$     | J/P           | -    | 2.0   | -     | $R_G(\text{on/off})=3.3/3.3\Omega$ (3)  |
| Reverse Recovery Loss                | $E_{rr}$      | J/P           | -    | 0.8   | -     | $V_{GE}=\pm 15\text{V}, T_{vj}=150^\circ\text{C}$                               |
| Stray inductance module              | $L_{SCE}$     | nH            | -    | 7     | -     | Collector Main to Emitter Main  |
| Thermal Impedance                    | IGBT          | $R_{th(j-c)}$ | -    | -     | 0.011 | Junction to case  |
|                                      | FWD           | $R_{th(j-c)}$ | -    | -     | 0.017 |   |
| Contact Thermal Impedance            | $R_{th(c-f)}$ | K/W           | -    | 0.005 | -     | Case to fin   |

Notes:(3)  $L_S$  and  $R_G$  are the test condition's values for evaluation of the switching times, not recommended value.

Please, determine the suitable  $R_G$  value after the measurement of switching waveforms (overshoot voltage, etc.) with appliance mounted.

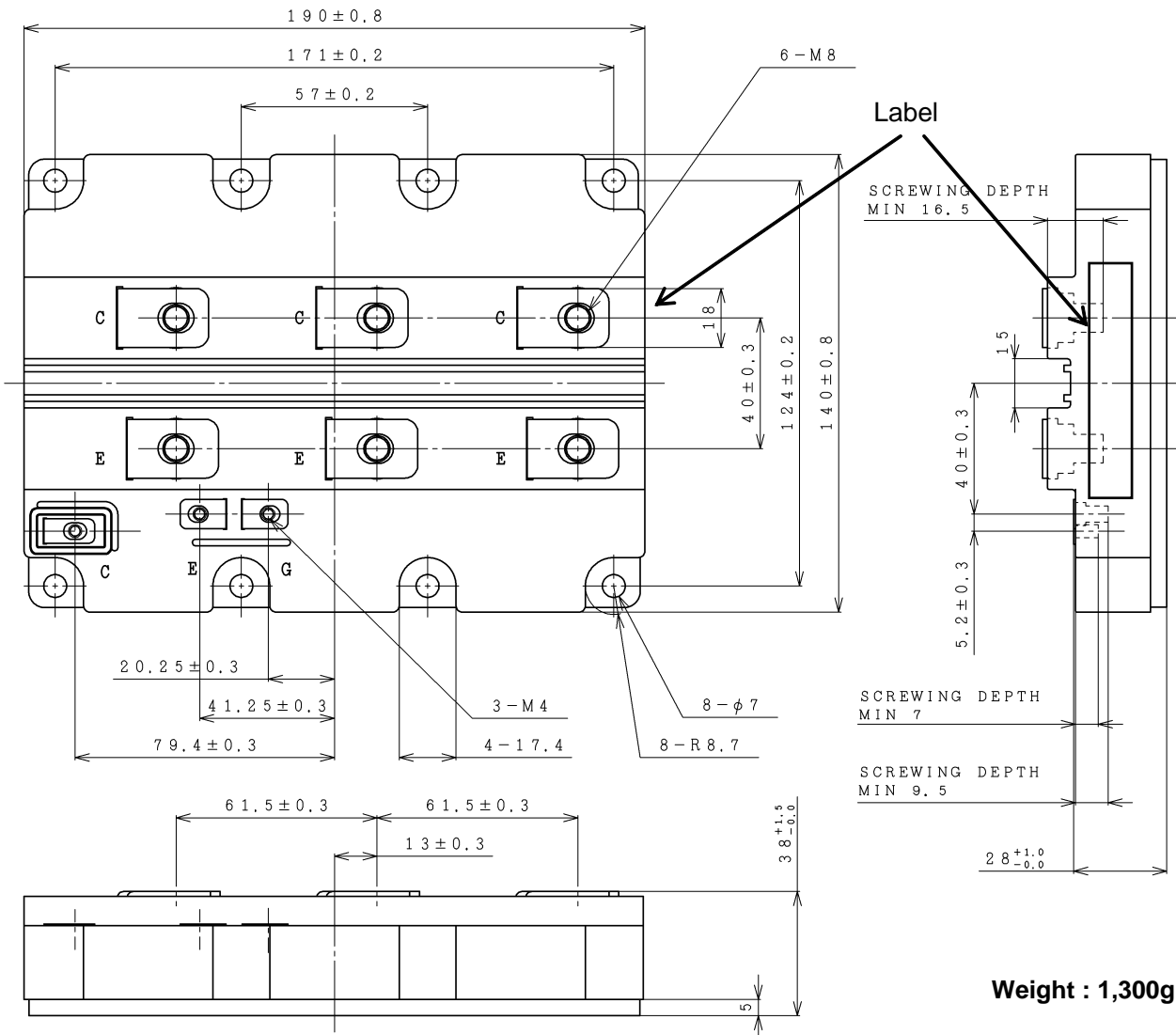
- \* Please contact our representatives at order.
- \* For improvement, specifications are subject to change without notice.
- \* For actual application, please confirm this spec sheet is the newest revision.
- \* ELECTRICAL CHARACTERISTIC items shown in above table are according to IEC 60747-2 and IEC 60747-9.

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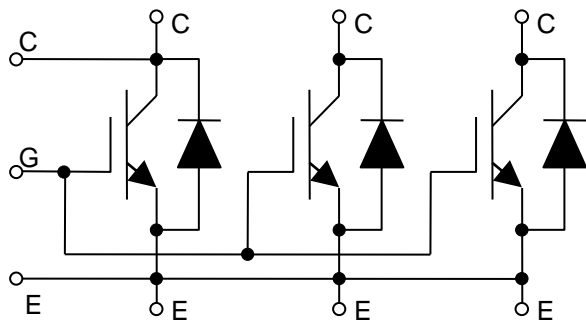
## OUTLINE DRAWING

Unit in mm



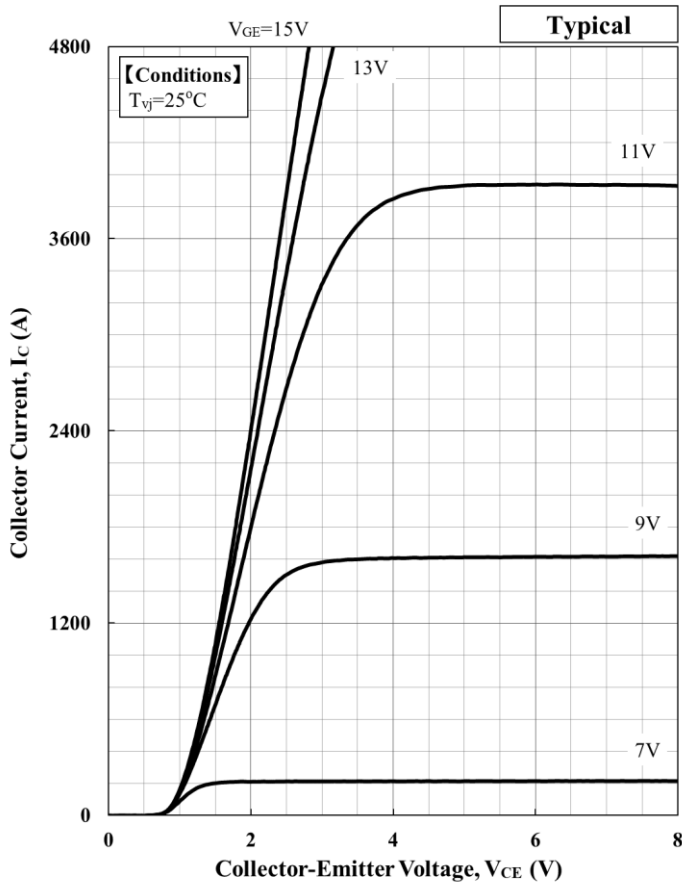
Weight : 1,300g

## CIRCUIT DIAGRAM

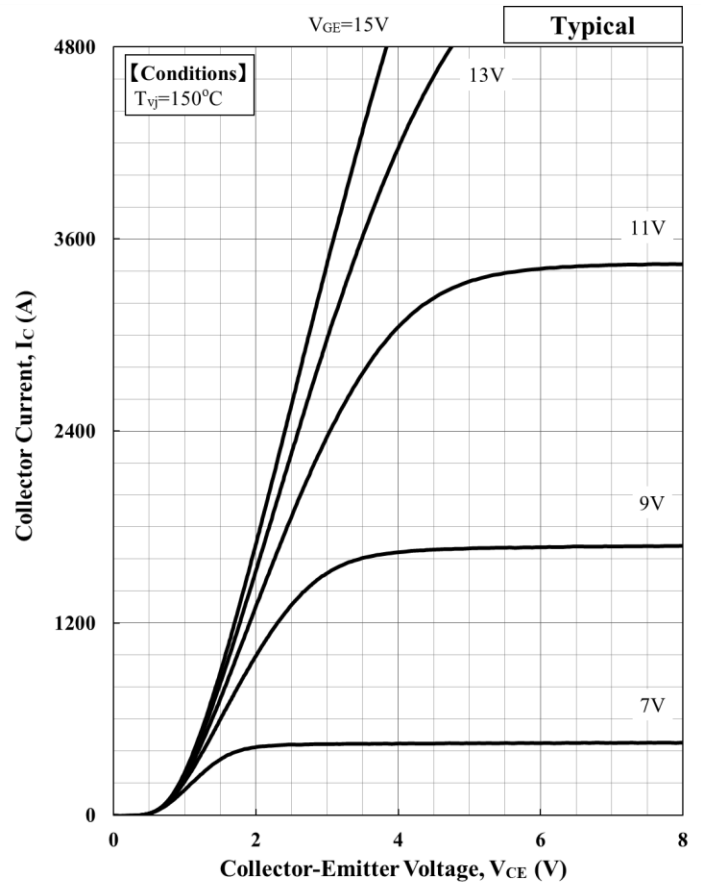


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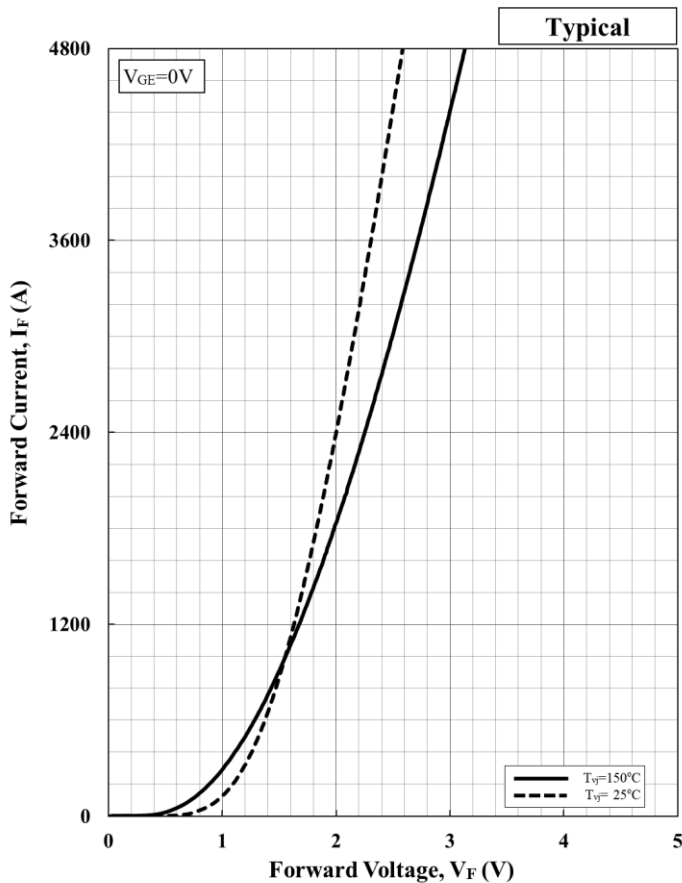
Preliminary Specification



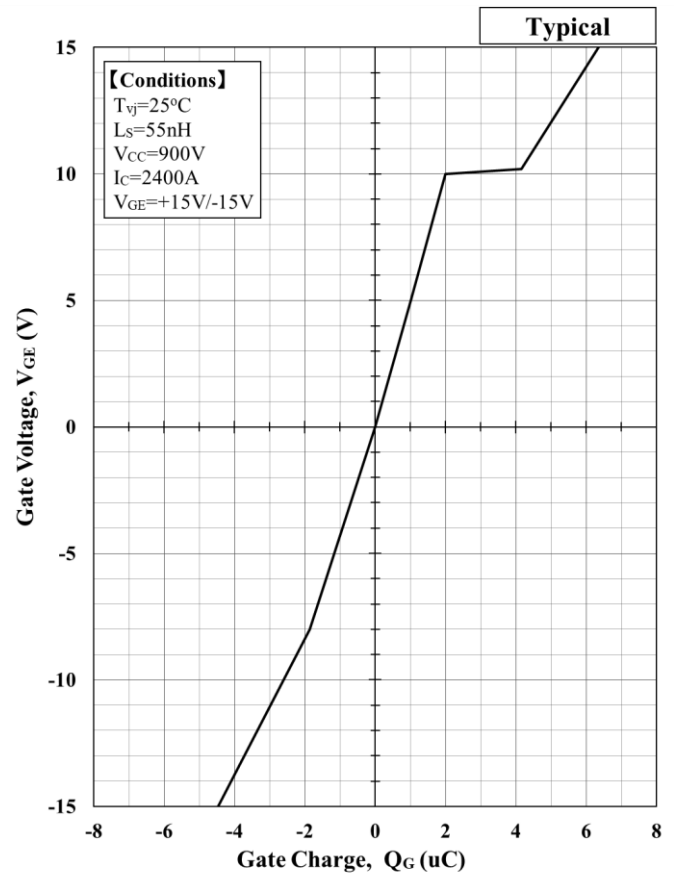
Collector Current vs. Collector Emitter Voltage



Collector Current vs. Collector Emitter Voltage



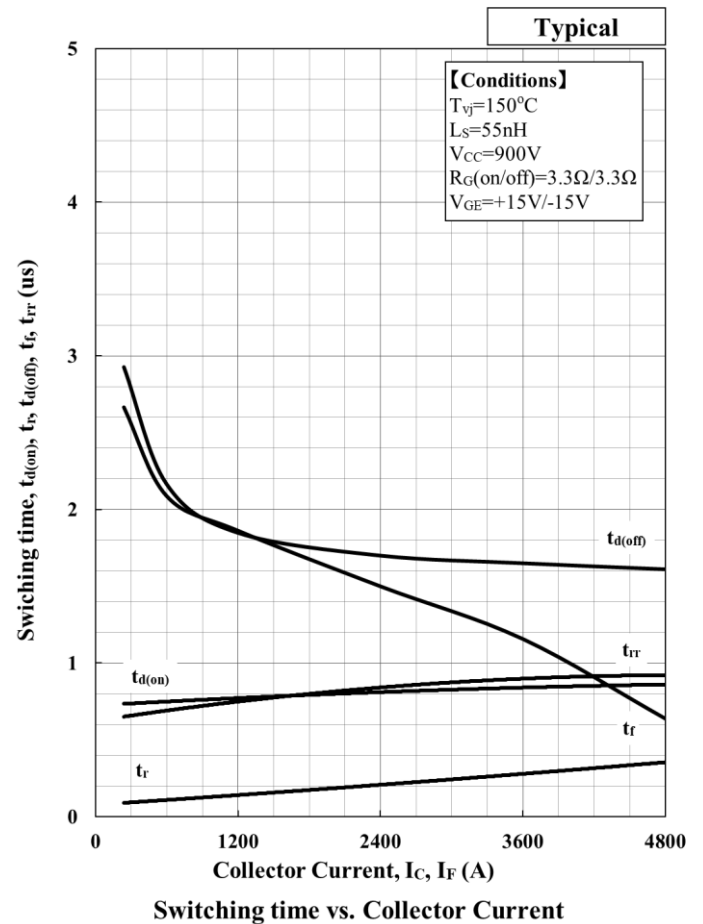
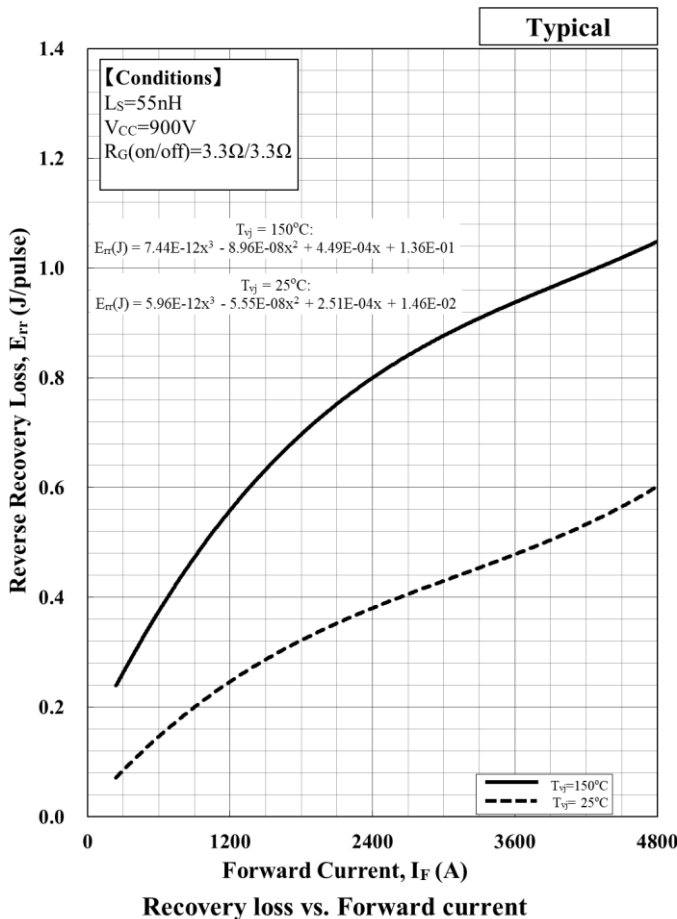
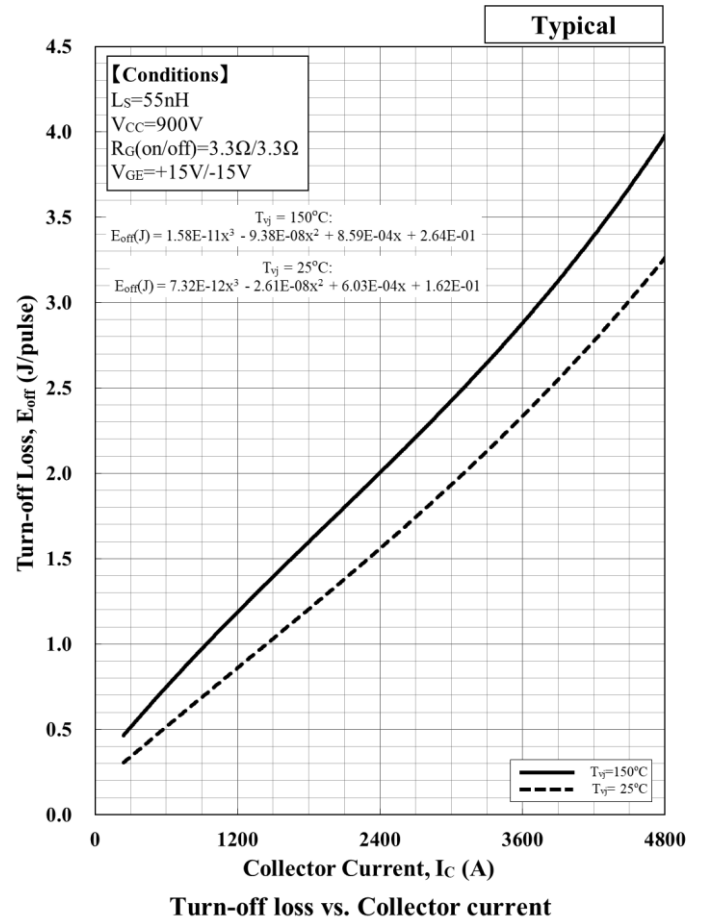
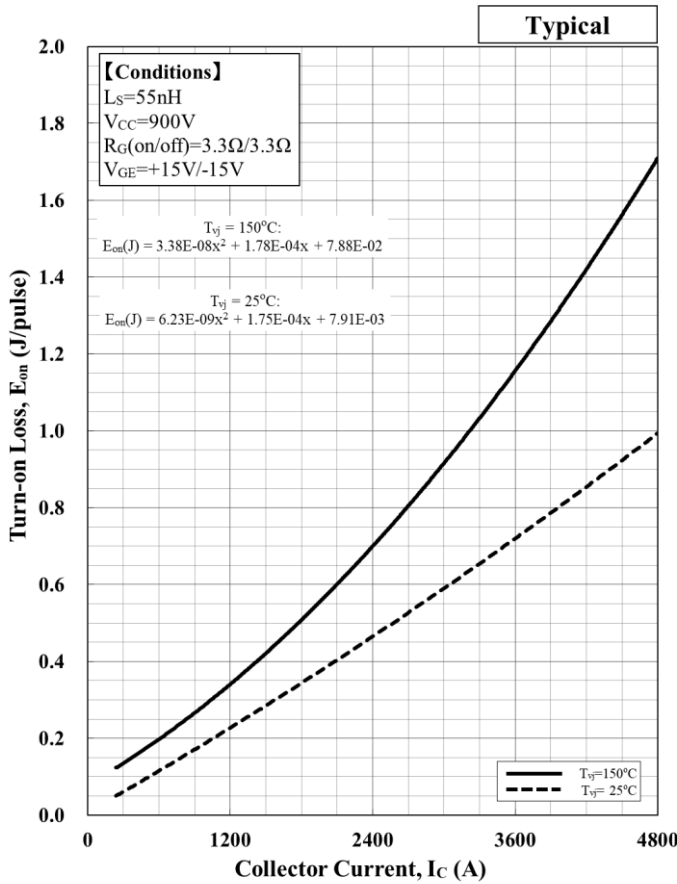
Forward Voltage of free-wheeling diode



$V_{GE}-Q_G$  curve

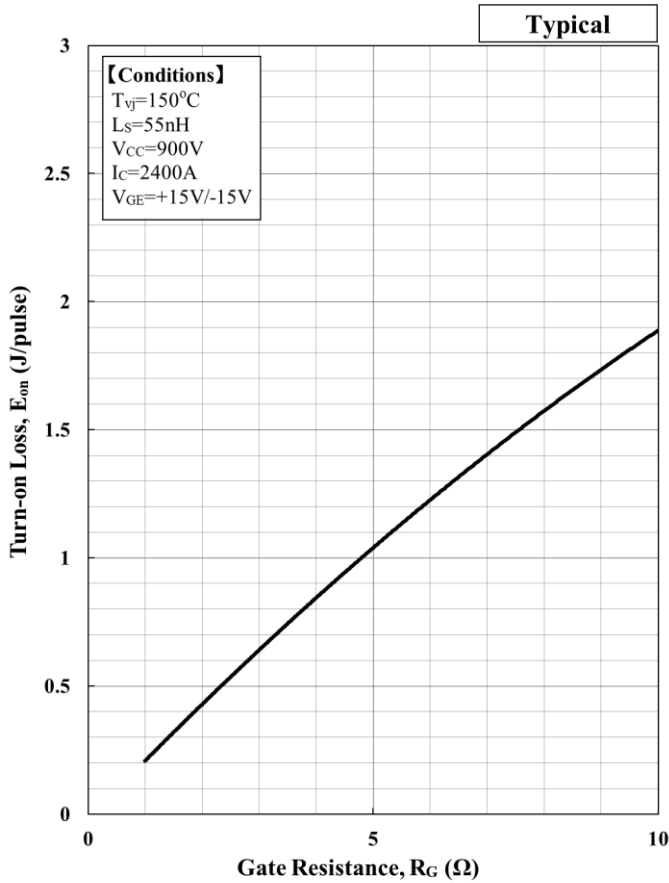
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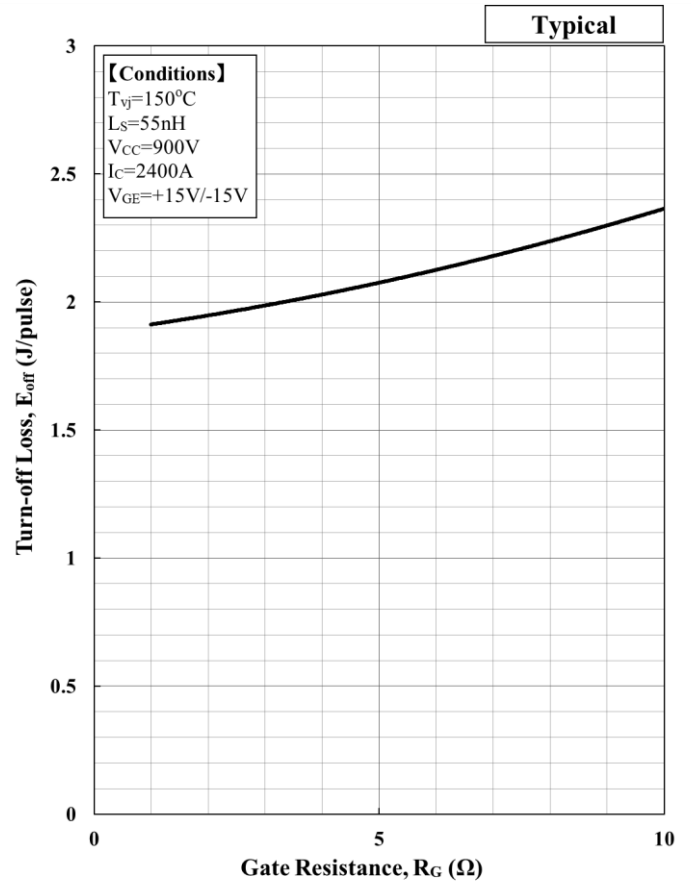


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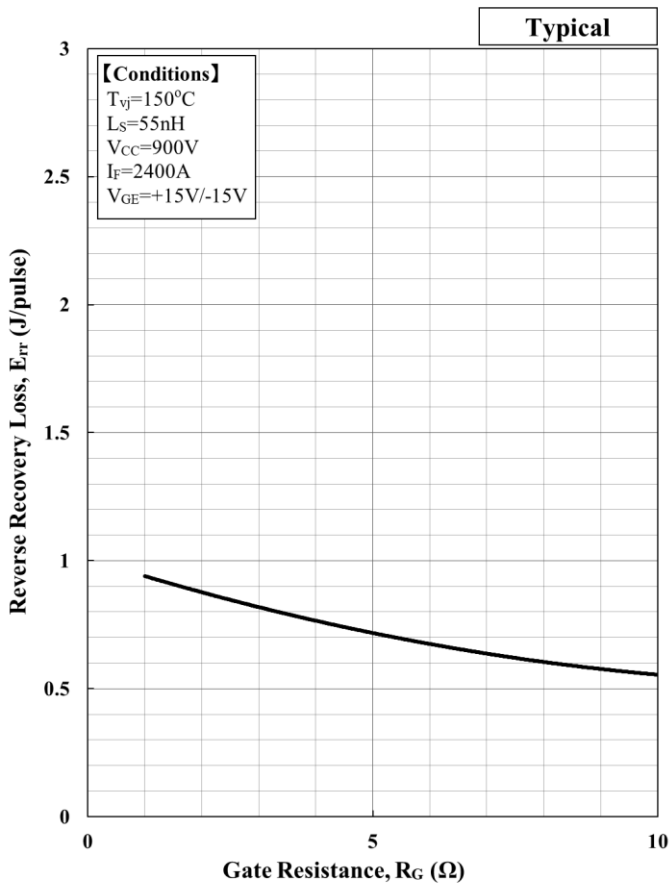
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Turn-on loss vs. Gate Resistance



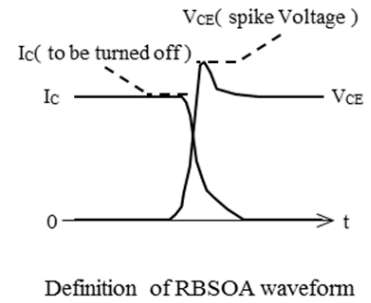
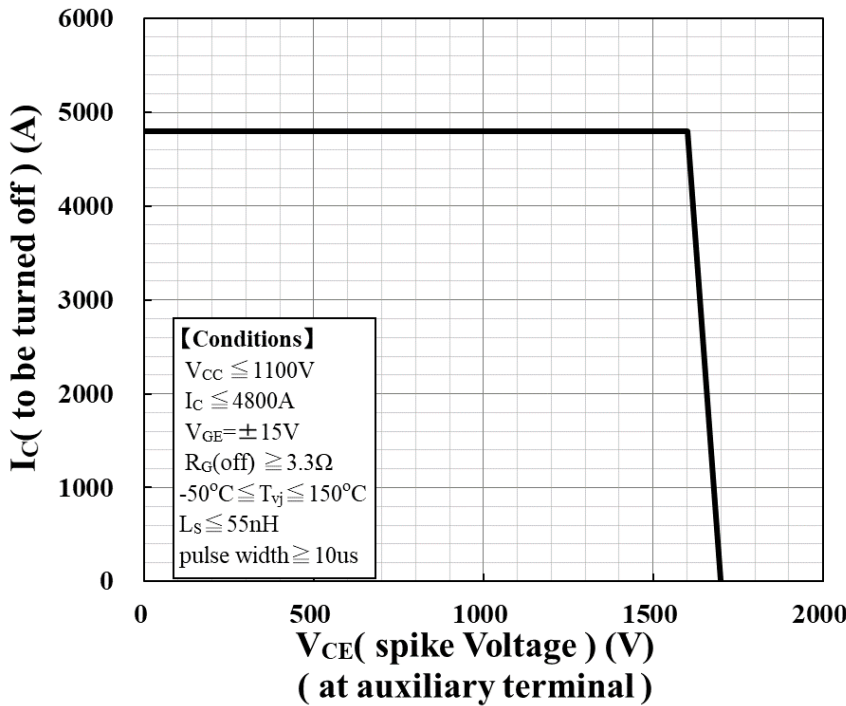
Turn-off loss vs. Gate Resistance



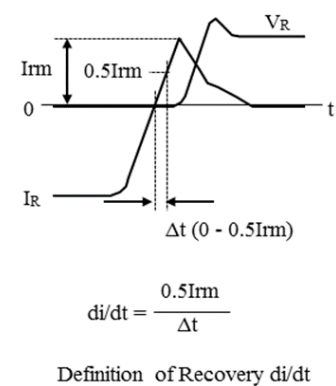
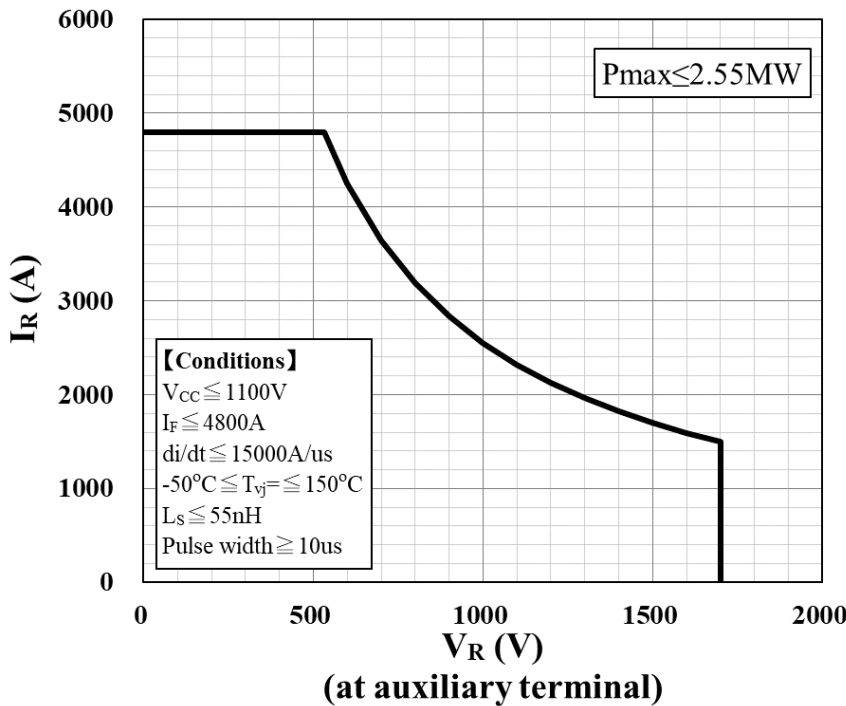
Recovery loss vs. Gate Resistance

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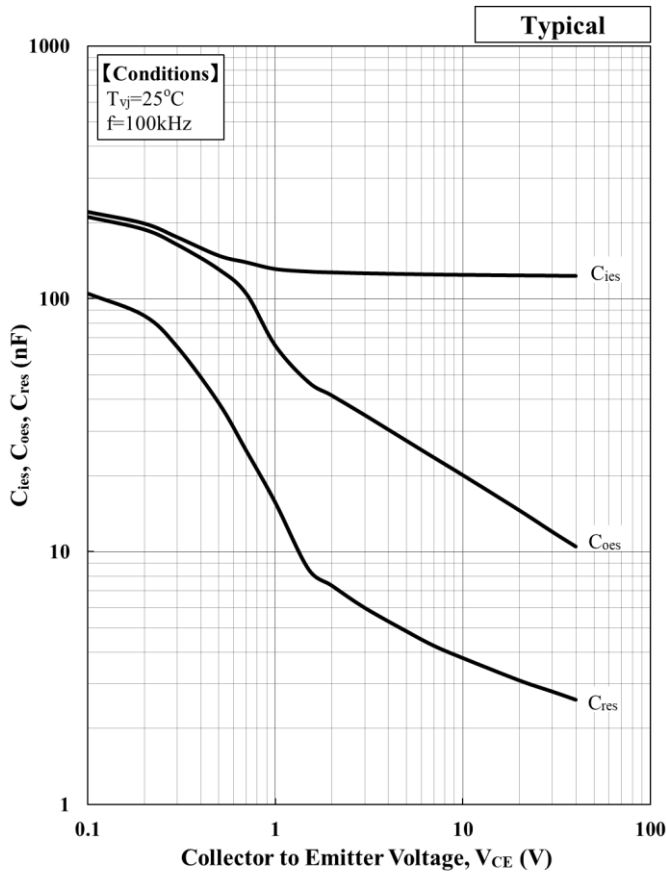
**Reverse Bias Safe Operation Area ( RBSOA )**



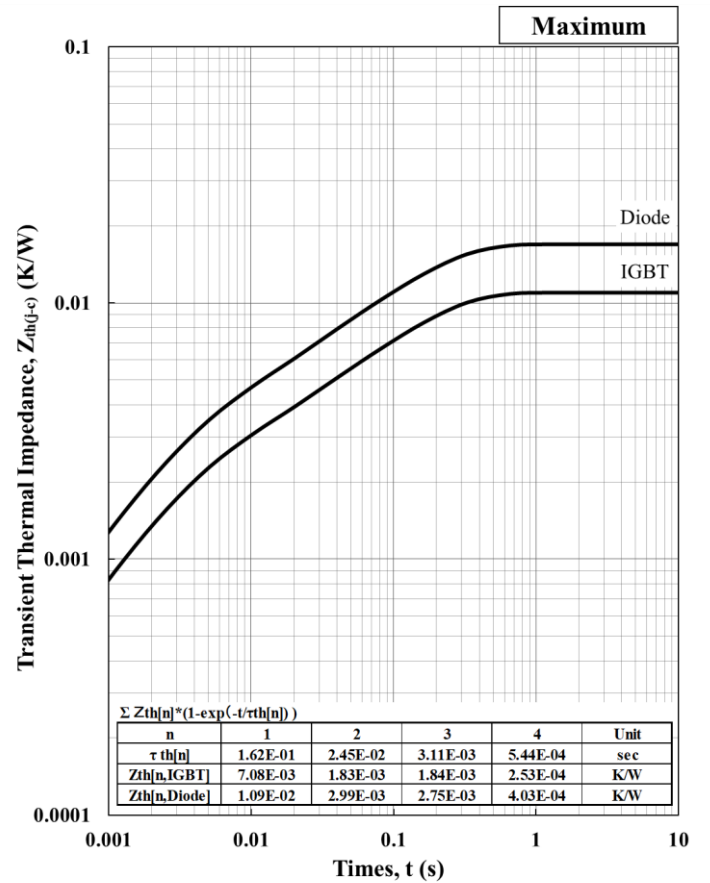
**Reverse Recovery Safe Operation Area ( RRSOA )**

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Capacitance vs. Collector to Emitter Voltage



Transient Thermal Impedance Curve

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Preliminary Specification

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